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1 **A thermal-aware superscalar microprocessor**
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1 **I have seen the future: it is flooded with email**
Reisman, S.;
Software, IEEE , Volume: 12 , Issue: 3 , May 1995
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[Abstract] [PDF Full-Text (196 KB)] **IEEE JNL**

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3 **Persistence and lurkers in discussion lists: a pilot study**
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5 **ADTP: a new protocol for data processing over the internet**
Kwak, J.D.; Elmasri, R.; Wook Choi; Rung-Chi Ye; Mahareddy, A.;
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[Abstract] [PDF Full-Text (320 KB)] **IEE CNF**

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System Sciences, 2000. Proceedings of the 33rd Annual Hawaii International Conference on , 4-7 Jan. 2000
Pages:10 pp.

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Pages:2/1 - 210

[Abstract] [PDF Full-Text (552 KB)] **IEE CNF**

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